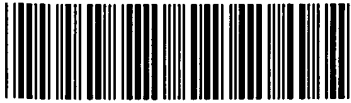


Search Notes

Application/Control No.

10/734,136

Examiner

Anne M. Hines

Applicant(s)/Patent under
Reexamination

HAN, IN-TAEK

Art Unit

2879

SEARCHED

Class	Subclass	Date	Examiner
313	503	6/23/05	Amth

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
consulted M. Santiago	8/22/2005	Amth
searched East; see search history	8/22/2005	Amth